

Amendment of April 23, 1998

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Title: METHOD OF PLANARIZING TIPS OF PROBE ELEMENTS OF A PROBE CARD ASSEMBLY (As Amended)

Inventor(s): Eldridge, et al.

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To: Commissioner of Patents and Trademarks  
Washington, D.C. 20231

AMENDMENT

Please enter this amendment.

In the Claims

Please amend the claims, as follows:

34. (TWICE AMENDED) [Method of planarizing tips] In a probe card assembly, a method of altering the orientation of probe elements for probing semiconductor devices [of a probe card assembly], comprising:

providing a probe card;

providing a support substrate with plurality of probe elements for probing semiconductor devices [a support substrate [having a top surface, a bottom surface, and a plurality of probe elements extending from the top surface, each probe element having a tip at an end distal from the top surface of the support substrate];

mounting the support substrate on [a] the probe card [having a top surface, the bottom surface of the support substrate opposing the top surface of the probe card, said support substrate having an orientation, said probe card having an orientation]; and

[adjusting] altering the orientation of the support substrate relative to the probe card [ without altering the orientation of the probe card, so as to planarize the tips of the probe elements ] .